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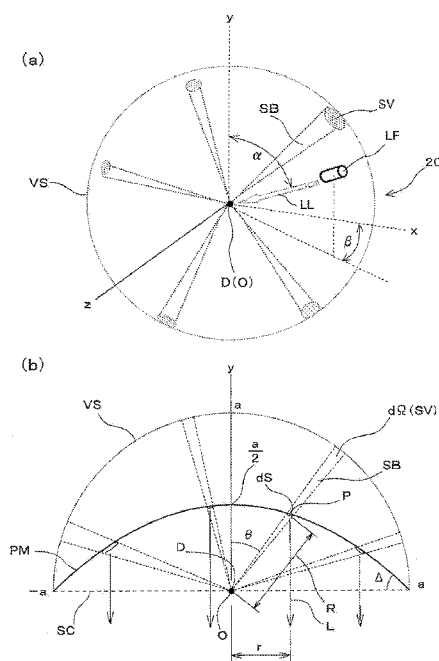
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(54) Title: DEVICE FOR MEASURING PROPERTIES OF SCATTERERS, COLOR MEASURING DEVICE FOR SCATTERED LIGHT OF GEMSTONES, DEVICE FOR MEASURING BRIGHTNESS OF GEMSTONES, AND DEVICE FOR MEASURING LUMINESCENCE DISTRIBUTION

[Fig. 1]



(57) Abstract: A device for measuring properties of scatterers which measures properties of a scatterer from a stereoscopic scattering distribution of the scatterer upon receiving an electromagnetic wave with a certain wavelength distribution is provided. In the device, a scatterer to be measured is placed on a specimen platform; the electromagnetic wave is irradiated onto the scatterer from at least either any one or more directions, or one or more continuous directions of a hypothetical spherical surface having the above-mentioned focal point as its center; scattering waves scattered by the scatterer and reflected off the paraboloidal mirror or projected onto the paraboloidal screen are imaged by the imaging means as planar imaging data; and from thus obtained imaging data, a stereoscopic distribution of the scattering waves generated by the scatterer is obtained so as to measure properties of the scatterer from the distribution result.



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